12. Akronimi metoda/uređaja/instrumenata

AKRONIMI	METODE-UREĐAJI-INSTRUMENTI
3DAP	3-dimensional atom probe
AAS	Atomic absorption spectroscopy
ADES	Angle dispersed electron spectroscopy
AED	Auger electron diffraction
AEM	Analytical electron microscopy
AES	Auger emission (electron) spectrometry; *Auger-ova emisijska spektroskopija*
AEFS	Absorption edge fine structure
AETEM	Atomic-resolution environmental transmission electron microscopy
AFAM	Atomic-force acoustic microscopy
AFM	Atomic force microscopy
APFIM	Atomic probe field ion microscopy
APS	Appearance potential spectroscopy
ARP(ES)	Angle-resolved photoemission (spectroscopy)
ATEM	Analytical transmission electron microscopy
ATR	Attenuated total reflectance
AXRS	Anomalous X-ray scattering
BET	BET surface area measurement
BiFC	Bimolecular fluorescence complementation
BKD	Backscatter Kikuchi diffraction
BLE	Bombardment-induced light emission
BRET	Bio-luminescence resonance energy transfer
BSE	Back scattered electrons
BSED	Back scattered electron diffraction
CAFM	Conducting atomic force microscopy
CAICISS	Coaxial impact collision ion scattering spectroscopy
CBD	Convergent beam diffraction
CBED	Convergent beam electron diffraction
CCM	Charge collection microscopy
CDI	Coherent diffraction imaging
CEMS	Conversion electron Mössbauer spectroscopy
CET	Cryo-electron tomography
CFM	Chemical force microscopy
CIS	Constant initial state spectroscopy
CL	Cathodo-luminescence
CLSM	Confocal laser scanning microscopy
CMR	Contact microradiography
COSY	Correlation spectroscopy
CPAA	Charge particle activation analysis
Cryo-EM	Cryo-electron microscopy
CS-AFM	Current-sensing atomic force microscopy
CTEM	Conventional transmission electron microscopy (TEM)
CTXM	Conventional scanning X-ray microscopy
CV	Cyclic voltametry
DAC	Diamond anvil cell
DE(T)A	Dielectric thermal analysis
dHvA	De Haas-van Alphen effect
DIC	Differential interference contrast microscopy
DLS	Dynamic light scattering
DLTS	Deep level transitient spectroscopy
DMA	Dynamic mechanical analysis
DPC	Differential phase contrast
DSC	Differential scanning calorimetry; *diferencijalna skenirajuća/pretražna kalorimetrija*

DTA	Differential thermal analysis; *diferencijalna termička analiza*
DVS	Dynamic vapor sorption
ECD	Electron coincidence spectroscopy
EBIC	Electron beam induce conductivity
EBSD	Electron backscatter diffraction
EBSP	Electron backscatter spectroscopy
ECOSY	Exclusive correlation spectroscopy
ECT	Electrical capacitance tomography
ED	Electron diffraction; *elektronska difrakcija*
EDS	Energy dispersive (X-ray) spectrometry
EDX	Energy dispersive (X-ray) spectroscopy/analysis
EELFS	Electron energy loss fine structure spectrometry
EEM	Emission electron microscopy
EFM	Electrostatic force microscope
EFTEM	Energy-filtering transmission electron microscopy
EMMA	Analytical electron microscopy with microanalysis
EELS	Electron energy loss spectrometry
EID	Electron induced desorption
EIT	Electrical impedance tomography
ELNES	Near-edge fine structure in EELS
ELS	Electropheric light scattering
ENDOR	Electron nuclear double resonance
EPES	Elastic peak electron spectroscopy
EPM(A)	Electron probe microanalysis
EPR	Electron paramagnetic resonance spectrometry
ERT	Electrical resistivity tomography
ESCA	Electron spectroscopy for chemical analysis
ESEM	Environmental scanning electron microscopy
ESD	Electron stimulated desorption
ESD(MS)	Electron stimulated desorption mass spectroscopy
ESI	Electron spectroscopic imaging
ES-MS	Electro spray mass spectrometry
ESI-MS	Electro spray ionization mass spectrometry
ESR	Electron spin resonance spectroscopy; *elektronsko spinska rezonancija*
ESTM	Electrochemical scanning tunneling microscopy
ETEM	Environmental transmission electron microscopy
EXAFS	Extended (X-ray) absorption fine structure spectroscopy
EXELFS	Extended (electron) energy loss fine structure
EXSY	Exchange spectroscopy
FAB(MS)	Fast atom bombardment mass spectroscopy
FCCS	Fluorescence cross-correlation spectroscopy
FCS	Fluorescence correlation spectroscopy
FE-AES	Field emission Auger electron spectroscopy
FEM	Field emission microscopy
FESEM	Field emission scanning electron microscopy
FFM	Friction force microscope
FIB	Focused ion beam microscopy
FIM	Field-ion microscope
FIM	Field-ion microscope-atom probe
FLIM	Fluorescence lifetime imaging
FRET	Fluorescence resonance energy transfer
FTICR	Fourier transform ion cyclotron resonance
FTIR	Fourier transform infrared absorption spectroscopy
FT-MS	Fourier-transform mass spectroscopy
GC-MS	Gas chromatography-mass spectrometry
GDMS	Glow discharge mass spectrometry

GDOES	Glow discharge optical spectroscopy
GDOS	Glow discharge optical spectrometry
GDS	Glow discharge spectroscopy
GISAXS	Grazing incidence small-angle X-ray scattering
GIXD	Grazing incidence X-ray diffraction
GIXR	Grazing incidence X-ray reflectivity
GLC	Gas-liquid chromatography
GSIMS	Gentle secondary ion mass spectroscopy
HAS	Helium atom scattering
HPLC	High performance liquid chromatography
HP-XPS	High-pressure X-ray photoelectron spectroscopy
HREELS	High resolution electron energy loss spectrometry
HRSEM	High-resolution scanning electron microscopy
HRTEM	High-resolution transmission electron microscopy; *visoko razlučujuća transmisijska elektronska mikroskopija*
HFCVD	Hot filament chemical vapor deposition
HVEM	High voltage electron microscopy
IABD	Ion beam assisted spectroscopy
IAES	Ion-induced Auger electron spectroscopy
IBM	Ion beam mixing
IBIC	Ion beam induced charge microscopy
ICP-MS	Inductively coupled plasma mass spectrometry
ICR	Ion cyclotron resonance
IETS	Inelastic electron tunneling spectroscopy
IGA	Intelligent gravimetric analysis
IIX	Ion induced X-ray analysis
IMP(A)	Ion microprobe analysis
INS	Ion neutralization spectroscopy (Inelastic neutron scattering)
IPE	Inverse photoemission
IR(S)	Infrared spectroscopy; *infracrvena spektroskopija*
ISS	Ion scattering spectroscopy
ITC	Isothermal titration calorimetry
IVEM	Intermediate voltage electron microscopy
LAD	Large angle diffraction
LALLS	Low-angle laser light scattering
LAMMA	Laser microprobe mass analysis
LAXS	Low angle X-ray scattering
LC-MS	Liquid chromatography-mass spectrometry
LEED	Low-energy electron diffraction; difrakcija elektrona niskih energija
LEELS	Low-energy electron loss spectrometry; *nisko-energijska elektronska gubitna spektroskopija*
LEEM	Low-energy electron microscopy; *nisko-energijska elektronska mikroskopija*
LEIS	Low energy ion (back) scattering
LFM	Lateral force microscopy
LIBS	Laser induced breakdown spectroscopy
LIMA	Laser induced ion mass analysis
LM	Light microscopy
LOES	Laser optical emission spectrometry
LS	Light (Raman) scattering
MALDI	Matrix-assisted laser desorption/ionization
MBE	Molecular beam epitaxy
MEIS	Medium energy ion scattering
MExFM	Magnetic exchange force microscopy
MFM	Magnetic force microscope
MIT	Magnetic induction tomography
MOCVD	Metal organic chemical vapor deposition

MOLE	Molecular optical laser examiner
MPCVD	Microwave plasma assisted chemical vapor deposition
MRFM	Magnetic resonance force microscopy
MRI	Magnetic resonance imaging
MS	Mass spectroscopy
MS	Mössbauer Spectroscopy; *Mössbauerova spektroskopija*
MS/MS	Tandem mass spectrometry
MTA	Micro-thermal analysis
NAA	Neutron activation analysis
ND	Neutron diffraction; *neutronska difrakcija*
NDP	Neutron depth profiling
NDT	Non-destructive testing
NEXAFS	Near-edge X-ray absorption fine structure
NIS	Neutron inelastic scattering
NLOS	Nonlinear optical spectroscopy; *nelinearna optička spektroskopija*
NMR	Nuclear Magnetic Resonance (Spectroscopy); *nuklearna magnetska rezonancija*
NOESY	Nuclear Overhauser effect spectrometry
NQR	Nuclear quadruple Resonance
NSOM	Near-field scanning optical microscopy
OES	Optical emission spectrometry
OIM	Orientation imaging microscopy
OM	Optical microscopy
PACT	Photoacustic computed tomography
PAM	Photoacustic microscopy
PAS	Positron-annihilation spectrometry
PALS	Positron annihilation lifetime spectroscopy
PACT	Photoacoustic computed tomography
PAT	Photoacoustic tomography
PAX	Photoemission of adsorbed xenon
PAS	Positron annihilation spectrometry
PC(S)	Photocurrent spectroscopy
PD	Photodesorption
PECVD	Plasma enhanced chemical vapor deposition
PED	Photoelectron diffraction
PEEM	photoemission electron microscopy
PESM	Photoelectron spectro microscopy
PEYS	Photoelectron spectroscopy
PFM	Photonic force microscopy
PIXE	Particle (proton) induced X-ray emission
PLD	Pulse laser deposition
PM-IRAS	Polarization modulated infrared reflection absorption spectroscopy
PSD(MS)	Photon-stimulated desorption mass spectroscopy
PTMS	Photo-thermal micro-spectrometry
PVD	Physical vapor deposition
QENS	Quasi-elastic neutron scattering
RAIRS	reflection absorption infrared spectroscopy
RAXRS	Resonant anomalous X-ray scattering
RBS	Rutherford backscattering spectroscopy; *Rutherfordovo odzivno raspršenje*
RDE	Reactive deposition epitaxy
RED	Reflection electron diffraction
REEL	Reflection electron energy-loss
REELS	Reflection electron energy-loss spectrometry
REFLEXAFS	Reflected extended X-ray absorption fine-structure spectroscopy
REM	Reflection electron microscopy
RHEED	Reflection high-energy electron diffraction; *visokoenergijska refleksijska elektronska difrakcija*

RIS	Rydberg ionization spectroscopy
RRS	Resonance Raman spectrometry
RS	Raman spectroscopy; *Ramanova spektroskopija*
SAM	Scanning Auger microscopy
SAM	Scanning acoustic microscopy
SANS	Small angle neutron scattering
SAXS	Small-angle X-ray scattering; *rentgenska difrakcija/raspršenje pod malim kutom*
SAXRD	Small-angle X-ray diffraction
SCANIIR	Surface composition by analysis of neutral species and ion-impact radiation
SCM	Scanning capacitance microscopy
SD	Sputter deposition
SE	Spectrometric ellipsometry
SEAM	Scanning electro acoustic microscopy
SEC	Size exclusion chromatography
SEM	Scanning electron microscopy; *rasterski/pretražni/skenirajući elektronski mikroskop*
SEIRA	Surface enhanced infrared absorption spectrometry
SERS	Surface enhanced Raman spectrometry/spectroscopy
SEXAFS	Surface extended x-ray absorption fine structure spectroscopy (Surface EXAFS)
SFA	Surface force apparatus
SICM	Scanning ion-conduction microscopy
SHEED	Scanning high energy electron diffraction
SICM	Scanning ion conductance microscopy
SIIMS	Secondary ion imaging mass spectrometry
SIMS	Secondary ion mass spectrometry; *masena spektroskopija sekundarnih iona*
SIPS	Sputter-induced photon spectroscopy
SLAM	Scanning laser acoustic microscopy
SNMS	Secondary neutral mass spectroscopy
SNOM	Scanning near-field optical microscopy
SOM	Scanning optical microscopy
SOMSEM	SOM in SEM
SPAM	Scanning photo acoustic microscopy
SPECT	Single photon emission computed tomography
SPM	Scanning probe microscopy
SPR	Surface plasmon resonance
SP-STM	Spin-polarized scanning-tunneling microscope/microscopy
SQUID	Superconducting quantum interference device
SRM-CE/MS	Selected-reaction-monitoring capillary-electrophoresis mass-spectrometry
SSNMR	Solid-state nuclear magnetic resonance
STEM	Scanning transmission electron microscopy
STM	Scanning tunneling microscope; *rasterski/pretražni tunelirajući mikroskop*
STXM	Scanning transmission X-ray microscopy
SXE	Soft X-ray emission
SXM	Scanning X-ray microscopy
TAT	Thermo-acoustic tomography
TACT	Thermo-acoustic computed tomography
TDP	Temperature programmed desorption
TEM	Transmission electron microscopy; *Transmisijska elektronska mikroskopija*
TFM	Thermic force microscope
TEM-EPMA	Transmission electron microscopy with electron probe microanalysis
THEED	Transmission high energy electron diffraction
TG(A)	Thermogravimetry (analysis); *termogravimetrija*
TIRFM	Total internal reflection fluorescence microscopy
TL	Termoluminescence
TMA	Thermo-mechanical analysis
TOF-SIMS	Time of flight secondary ion mass spectrometry
TRXRD	Time resolved X-ray diffraction

TXRF	Total X-ray reflection fluorescence spectroscopy (analysis)
UHRTEM	Ultra high-resolution transmission electron microscopy
UHVCVD	Ultra high vacuum chemical vapor deposition
UPS	Ultraviolet photoelectron/photoemission spectroscopy
VEDIC	Video-enhanced differential interference contrast microscopy
μPS	Muon-precession spectrometry
XAES	X-ray induced Auger electron spectrometry
XAFS	X-ray absorption fine structure spectroscopy
XANES	X-ray absorption near edge structure
XAS	X-ray absorption spectrometry
X-CTR	X-ray crystal truncation rod scattering
XDS	X-ray diffuse scattering
XPEEM	X-ray photoelectron emission microscopy
XPS	X-ray photoelectron/photoemission spectroscopy
XR	X-ray reflectivity
XRD	X-ray diffraction; *rentgenska difrakcija*
XRF	X-ray fluorescence (analysis); *rentgenska fluorescencija*
XRM	X-ray microscopy
XSW	X-ray standing wave technique
WAXS	Wide angle X-ray scattering
WDS (WDXEF)	Wavelength-dispersive spectrometry

AKRONIMI NEKIH NAZIVA

AC	Alternating current
APPJ	Atmospheric pressure plasma jet
ATR	Attenuated total reflectance
BEN	Bias enhanced nucleation
BGA	Bulk glassy alloy
BMG	Bulk metallic glass
CEOS	Image C_s corrector (u elektronskom mikroskopu za poboljšanje razlučivanja)
CMOS	Complementary metal oxide semiconducstor
CPMAR	Cross polarization magic angle rotation
CET	Capacitance equivalent thickness
CLIC	Compact linear collider
CPMAS	Cross polarization magic angle spinning
DAC	Diamond anvil cell
DC	Direct current
DFT	Density functional theory
DLC	Diamond like carbon
DSMC	Direct simulation Monte Carlo
DWCNT	Double-wall carbon nanotube
ECAP	Equal channel angular pressing
ECP	Electron channeling pattern
ED	Electro-deposition
EDC	Energy distribution curve
EFE	Electron field emission
ELPEC	Electrode less PEC
EPES	Elastic peak electron spectra
ERDA	Elastic recoil detection analysis
FEED	Field emission energy distributions
FEG	Field emission gun
FET	Field effect transistor
FIB	Focused ion beam
FFT	Fast Fourier transformation
GFA	Glass-forming ability
GIF	Gatan image filter

GMR	Giant magnetoresistance
HAADF	High-angle annular dark field
HCD	Hollow cathode discharge
HEMTs	high electron mobility transistors
HOLZ	Higher order Laue zone
HPT	High pressure torsion
IBM	Ion beam mixing
IMFP	Inelastic mean free path
IGC	Inert gas condensation
ITO	Indium-tin oxide
LED	Light-emittinc diode
LHC	Large hadron collider
MA	Mechanical alloying
MEMS	Micro-electron mechanical devices
MG	Mechanical grinding
MM	Mechanical milling
(M)NRs	**M** je oznaka za neki element, primjerice: **SiNRs** –Silicon nanorods; **CNRs**- Carbon nanorods
MRAM	Magnetoresistive random access memory
MWCNT	Multi-wall carbon nanotube
NCD	Nanocrystalline diamond
NEG	Non-evaporable getter
NIM	Negative-index material
NLOP	Non-linear optical property
NSLS	National synchrotron light source (Brookhaven National Laboratory)
PA	Polyamide
PBG	Photonic band gap
PEC	Photo-electrochemical
PET	Polyethylene terepthalate
PMMA	Polymethyl methacrylate
PS	Polystyrene
RDE	Reactive deposition epitaxy
RDF	Radial distribution function
RSM	Response surface methodology
SACP	Selected area channeling pattern
SAD	Selected area diffraction
SAED	Selected area electron diffraction
SAW	Surface acoustic wave
SDP	Severe plastic deformation
SE	Secondary electron
SES	Secondary electron emission
SEP	Surface excitation (material) parameter
SFG	Sum frequency generation
SPD	Severe plastic deformation
SSAR	Solid-state amorphization
SWCNT	Single-wall carbon nanotubes
TCO	Transparent conducting oxides
TCP	Transmission channeling pattern
TCR (TCRF)	Temperature coefficients of resistance
TFS	Thin film system
TOF	Time of flight
UHV	Ultrahigh vacuum
XMCD	X-ray magnetic circular dichroism
WCA	Water contact angle
WF	Work function
ZAF	Atomic number, absorption and fluorescence correction pattern